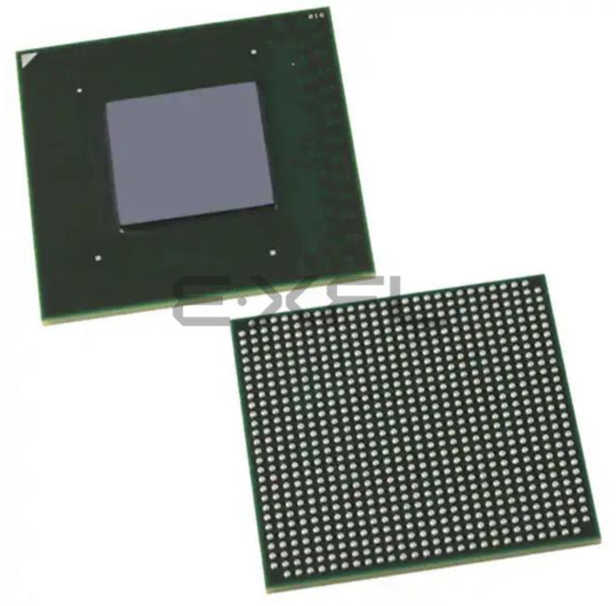
Intel - EP2AGX45DF29I3N Datasheet



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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	1805
Number of Logic Elements/Cells	42959
Total RAM Bits	3517440
Number of I/O	364
Number of Gates	-
Voltage - Supply	0.87V ~ 0.93V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	780-BBGA, FCBGA
Supplier Device Package	780-FBGA (29x29)
Purchase URL	https://www.e-xfl.com/product-detail/intel/ep2agx45df29i3n

Table 1–6. Recommended Operating Conditions for Arria II GZ Devices ***(Note 6)*** **(Part 2 of 2)**

Symbol	Description	Condition	Minimum	Typical	Maximum	Unit
V_{CCL_GXBLn} *(3)*	Transceiver clock power (left side)	—	1.05	1.1	1.15	V
V_{CCL_GXBRn} *(3)*	Transceiver clock power (right side)	—	1.05	1.1	1.15	V
V_{CCH_GXBLn} *(3)*	Transmitter output buffer power (left side)	—	1.33/1.425	1.4/1.5 *(5)*	1.575	V
V_{CCH_GXBRn} *(3)*	Transmitter output buffer power (right side)	—				
T_J	Operating junction temperature	Commercial	0	—	85	°C
		Industrial	–40	—	100	°C
t_{RAMP}	Power supply ramp time	Normal POR (PORSEL=0)	0.05	—	100	ms
		Fast POR (PORSEL=1)	0.05	—	4	ms

Notes to Table 1–6:

(1) Altera recommends a 3.0-V nominal battery voltage when connecting V_{CCBAT} to a battery for volatile key backup. If you do not use the volatile security key, you may connect the V_{CCBAT} to either GND or a 3.0-V power supply.

(2) V_{CCPD} must be 2.5 V when V_{CCIO} is 2.5, 1.8, 1.5, or 1.2 V. V_{CCPD} must be 3.0 V when V_{CCIO} is 3.0 V.

(3) n = 0, 1, or 2.

(4) $V_{CCA\_L/R}$ must be connected to a 3.0-V supply if the clock multiplier unit (CMU) phase-locked loop (PLL), receiver clock data recovery (CDR), or both, are configured at a base data rate > 4.25 Gbps. For data rates up to 4.25 Gbps, you can connect $V_{CCA\_L/R}$ to either 3.0 V or 2.5 V.

(5) $V_{CCH\_GXBL/R}$ must be connected to a 1.4-V supply if the transmitter channel data rate is > 6.5 Gbps. For data rates up to 6.5 Gbps, you can connect $V_{CCH\_GXBL/R}$ to either 1.4 V or 1.5 V.

(6) Transceiver power supplies do not have power-on-reset (POR) circuitry. After initial power-up, violating the transceiver power supply operating conditions could lead to unpredictable link behavior.

DC Characteristics

This section lists the supply current, I/O pin leakage current, on-chip termination (OCT) accuracy and variation, input pin capacitance, internal weak pull-up and pull-down resistance, hot socketing, and Schmitt trigger input specifications.

Supply Current

Standby current is the current the device draws after the device is configured with no inputs or outputs toggling and no activity in the device. Because these currents vary largely with the resources used, use the Microsoft Excel-based Early Power Estimator (EPE) to get supply current estimates for your design.

For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter.

Table 1–11. OCT With and Without Calibration Specification for Arria II GX Device I/Os *(Note 1)* (Part 2 of 2)

Symbol	Description	Conditions (V)	Calibration Accuracy		Unit
			Commercial	Industrial	
50-Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2	50-Ω series OCT with calibration	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	± 10	± 10	%
100-Ω R_D 2.5	100-Ω differential OCT without calibration	V_{CCIO} = 2.5	± 30	± 30	%

Note to Table 1–11:

(1) OCT with calibration accuracy is valid at the time of calibration only.

Table 1–12 lists the OCT termination calibration accuracy specifications for Arria II GZ devices.

Table 1–12. OCT with Calibration Accuracy Specifications for Arria II GZ Devices *(Note 1)*

Symbol	Description	Conditions (V)	Calibration Accuracy			Unit
			C2	C3,I3	C4,I4	
25-Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2 *(2)*	25-Ω series OCT with calibration	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	± 8	± 8	± 8	%
50-Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2	50-Ω internal series OCT with calibration	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	± 8	± 8	± 8	%
50-Ω R_T 2.5, 1.8, 1.5, 1.2	50-Ω internal parallel OCT with calibration	V_{CCIO} = 2.5, 1.8, 1.5, 1.2	± 10	± 10	± 10	%
20-Ω , 40-Ω , and 60-Ω R_S 3.0, 2.5, 1.8, 1.5, 1.2 *(3)*	20-Ω , 40-Ω and 60-Ω R_S expanded range for internal series OCT with calibration	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	± 10	± 10	± 10	%
25-Ω $R_{S\_left\_shift}$ 3.0, 2.5, 1.8, 1.5, 1.2	25-Ω $R_{S\_left\_shift}$ internal left shift series OCT with calibration	V_{CCIO} = 3.0, 2.5, 1.8, 1.5, 1.2	± 10	± 10	± 10	%

Notes to Table 1–12:

(1) OCT calibration accuracy is valid at the time of calibration only.

(2) 25-Ω R_S is not supported for 1.5 V and 1.2 V in Row I/O.

(3) 20-Ω R_S is not supported for 1.5 V and 1.2 V in Row I/O.

The calibration accuracy for calibrated series and parallel OCTs are applicable at the moment of calibration. When process, voltage, and temperature (PVT) conditions change after calibration, the tolerance may change.

Table 1–13 lists the Arria II GZ OCT without calibration resistance tolerance to PVT changes.

Table 1–13. OCT Without Calibration Resistance Tolerance Specifications for Arria II GZ Devices

Symbol	Description	Conditions (V)	Resistance Tolerance		Unit
			C3,I3	C4,I4	
25-Ω R_S 3.0 and 2.5	25-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
25-Ω R_S 1.8 and 1.5	25-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
25-Ω R_S 1.2	25-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
50-Ω R_S 3.0 and 2.5	50-Ω internal series OCT without calibration	V_{CCIO} = 3.0, 2.5	± 40	± 40	%
50-Ω R_S 1.8 and 1.5	50-Ω internal series OCT without calibration	V_{CCIO} = 1.8, 1.5	± 40	± 40	%
50-Ω R_S 1.2	50-Ω internal series OCT without calibration	V_{CCIO} = 1.2	± 50	± 50	%
100-Ω R_D 2.5	100-Ω internal differential OCT	V_{CCIO} = 2.5	± 25	± 25	%

OCT calibration is automatically performed at power up for OCT-enabled I/Os. When voltage and temperature conditions change after calibration, the resistance may change. Use Equation 1–1 and Table 1–14 to determine the OCT variation when voltage and temperature vary after power-up calibration for Arria II GX and GZ devices.

Equation 1–1. OCT Variation *(Note 1)*

$$R_{OCT} = R_{SCAL}\left(1 + \langle\frac{dR}{dT} \times \Delta T\rangle \pm \langle\frac{dR}{dV} \times \Delta V\rangle\right)$$

Notes to Equation 1–1:

(1) R_{OCT} value calculated from Equation 1–1shows the range of OCT resistance with the variation of temperature and V_{CCIO}.

Use the following with Equation 1–1:

- R_{SCAL} is the OCT resistance value at power up.
- ΔT is the variation of temperature with respect to the temperature at power up.
- ΔV is the variation of voltage with respect to the V_{CCIO} at power up.
- dR/dT is the percentage change of R_{SCAL} with temperature.
- dR/dV is the percentage change of R_{SCAL} with voltage.

Table 1–14 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GX devices.

Table 1–14. OCT Variation after Power-up Calibration for Arria II GX Devices

Nominal Voltage V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.262	0.035
2.5	0.234	0.039
1.8	0.219	0.086
1.5	0.199	0.136
1.2	0.161	0.288

Table 1–15 lists the OCT variation with temperature and voltage after power-up calibration for Arria II GZ devices.

Table 1–15. OCT Variation after Power-Up Calibration for Arria II GZ Devices *(Note 1)*

Nominal Voltage, V_{CCIO} (V)	dR/dT (%/°C)	dR/dV (%/mV)
3.0	0.189	0.0297
2.5	0.208	0.0344
1.8	0.266	0.0499
1.5	0.273	0.0744
1.2	0.317	0.1241

Note to Table 1–15:

(1) Valid for V_{CCIO} range of ±5% and temperature range of 0° to 85°C.

Pin Capacitance

Table 1–16 lists the pin capacitance for Arria II GX devices.

Table 1–16. Pin Capacitance for Arria II GX Devices

Symbol	Description	Typical	Unit
C_{IO}	Input capacitance on I/O pins, dual-purpose pins (differential I/O, clock, R_{up}, R_{dn}), and dedicated clock input pins	7	pF

Table 1–17 lists the pin capacitance for Arria II GZ devices.

Table 1–17. Pin Capacitance for Arria II GZ Devices

Symbol	Description	Typical	Unit
C_{IOTB}	Input capacitance on the top and bottom I/O pins	4	pF
C_{IOLR}	Input capacitance on the left and right I/O pins	4	pF
C_{CLKTB}	Input capacitance on the top and bottom non-dedicated clock input pins	4	pF
C_{CLKLR}	Input capacitance on the left and right non-dedicated clock input pins	4	pF
C_{OUTFB}	Input capacitance on the dual-purpose clock output and feedback pins	5	pF
C_{CLK1}, C_{CLK3}, C_{CLK8}, and C_{CLK10}	Input capacitance for dedicated clock input pins	2	pF

Internal Weak Pull-Up and Weak Pull-Down Resistors

Table 1–18 lists the weak pull-up and pull-down resistor values for Arria II GX devices.

Table 1–18. Internal Weak Pull-up and Weak Pull-Down Resistors for Arria II GX Devices *(Note 1)*

Symbol	Description	Conditions	Min	Typ	Max	Unit
R_{PU}	Value of I/O pin pull-up resistor before and during configuration, as well as user mode if the programmable pull-up resistor option is enabled.	V_{CCIO} = 3.3 V ±5% *(2)*	7	25	41	kΩ
		V_{CCIO} = 3.0 V ±5% *(2)*	7	28	47	kΩ
		V_{CCIO} = 2.5 V ±5% *(2)*	8	35	61	kΩ
		V_{CCIO} = 1.8 V ±5% *(2)*	10	57	108	kΩ
		V_{CCIO} = 1.5 V ±5% *(2)*	13	82	163	kΩ
		V_{CCIO} = 1.2 V ±5% *(2)*	19	143	351	kΩ
R_{PD}	Value of TCK pin pull-down resistor	V_{CCIO} = 3.3 V ±5%	6	19	29	kΩ
		V_{CCIO} = 3.0 V ±5%	6	22	32	kΩ
		V_{CCIO} = 2.5 V ±5%	6	25	42	kΩ
		V_{CCIO} = 1.8 V ±5%	7	35	70	kΩ
		V_{CCIO} = 1.5 V ±5%	8	50	112	kΩ

Notes to Table 1–18:

(1) All I/O pins have an option to enable weak pull-up except configuration, test, and JTAG pins. The weak pull-down feature is only available for JTAG `TCK`.

(2) Pin pull-up resistance values may be lower if an external source drives the pin higher than V_{CCIO}.

Table 1–26 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GX devices.

Table 1–26. Single-Ended SSTL and HSTL I/O Standard Signal Specifications for Arria II GX Devices

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	–0.3	V_{REF} - 0.18	V_{REF} + 0.18	V_{CCIO} + 0.3	V_{REF} - 0.35	V_{REF} + 0.35	V_{TT} - 0.57	V_{TT} + 0.57	8.1	–8.1
SSTL-2 Class II	–0.3	V_{REF} - 0.18	V_{REF} + 0.18	V_{CCIO} + 0.3	V_{REF} - 0.35	V_{REF} + 0.35	V_{TT} - 0.76	V_{TT} + 0.76	16.4	–16.4
SSTL-18 Class I	–0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	V_{TT} - 0.475	V_{TT} + 0.475	6.7	–6.7
SSTL-18 Class II	–0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	0.28	V_{CCIO} - 0.28	13.4	–13.4
SSTL-15 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	8	–8
SSTL-15 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	16	–16
HSTL-18 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	–8
HSTL-18 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	–16
HSTL-15 Class I	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	–8
HSTL-15 Class II	–0.3	V_{REF} - 0.1	V_{REF} + 0.1	V_{CCIO} + 0.3	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	–16
HSTL-12 Class I	–0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	8	–8
HSTL-12 Class II	–0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25 × V_{CCIO}	0.75 × V_{CCIO}	14	–14

Table 1–27 lists the single-ended SSTL and HSTL I/O standard signal specifications for Arria II GZ devices.

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 1 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-2 Class I	-0.3	V_{REF} - 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} - 0.31	V_{REF} + 0.31	V_{TT} - 0.57	V_{TT} + 0.57	8.1	-8.1
SSTL-2 Class II	-0.3	V_{REF} - 0.15	V_{REF} + 0.15	V_{CCIO} + 0.3	V_{REF} - 0.31	V_{REF} + 0.31	V_{TT} - 0.76	V_{TT} + 0.76	16.2	-16.2
SSTL-18 Class I	-0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	V_{TT} - 0.475	V_{TT} + 0.475	6.7	-6.7
SSTL-18 Class II	-0.3	V_{REF} - 0.125	V_{REF} + 0.125	V_{CCIO} + 0.3	V_{REF} - 0.25	V_{REF} + 0.25	0.28	V_{CCIO} - 0.28	13.4	-13.4
SSTL-15 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	8	-8

Table 1–27. Single-Ended SSTL and HSTL I/O Standards Signal Specifications for Arria II GZ Devices (Part 2 of 2)

I/O Standard	$V_{IL(DC)}$ (V)		$V_{IH(DC)}$ (V)		$V_{IL(AC)}$ (V)	$V_{IH(AC)}$ (V)	V_{OL} (V)	V_{OH} (V)	I_{OL} (mA)	I_{OH} (mA)
	Min	Max	Min	Max	Max	Min	Max	Min		
SSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.175	V_{REF} + 0.175	0.2 × V_{CCIO}	0.8 × V_{CCIO}	16	-16
HSTL-18 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-18 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-15 Class I	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	8	-8
HSTL-15 Class II	—	V_{REF} - 0.1	V_{REF} + 0.1	—	V_{REF} - 0.2	V_{REF} + 0.2	0.4	V_{CCIO} - 0.4	16	-16
HSTL-12 Class I	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75× V_{CCIO}	8	-8
HSTL-12 Class II	-0.15	V_{REF} - 0.08	V_{REF} + 0.08	V_{CCIO} + 0.15	V_{REF} - 0.15	V_{REF} + 0.15	0.25× V_{CCIO}	0.75 × V_{CCIO}	16	-16

Table 1–28 lists the differential SSTL I/O standards for Arria II GX devices.

Table 1–28. Differential SSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.36	V_{CCIO}	V_{CCIO}/2 - 0.2	—	V_{CCIO}/2 + 0.2	0.7	V_{CCIO}	V_{CCIO}/2 - 0.15	—	V_{CCIO}/2 + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO}	V_{CCIO}/2 - 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO}	V_{CCIO}/2 - 0.125	—	V_{CCIO}/2 + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	V_{CCIO}/ 2	—	0.35	—	—	V_{CCIO}/ 2	—

Table 1–29 lists the differential SSTL I/O standards for Arria II GZ devices

Table 1–29. Differential SSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{SWING(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{SWING(AC)}$ (V)		$V_{OX(AC)}$ (V)		
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Max	Min	Typ	Max
SSTL-2 Class I, II	2.375	2.5	2.625	0.3	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.2	—	V_{CCIO}/2 + 0.2	0.62	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.15	—	V_{CCIO}/2 + 0.15
SSTL-18 Class I, II	1.71	1.8	1.89	0.25	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.175	—	V_{CCIO}/2 + 0.175	0.5	V_{CCIO} + 0.6	V_{CCIO}/2 - 0.125	—	V_{CCIO}/2 + 0.125
SSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	—	V_{CCIO}/ 2	—	0.35	—	—	V_{CCIO}/ 2	—

Table 1–30 lists the HSTL I/O standards for Arria II GX devices.

Table 1–30. Differential HSTL I/O Standards for Arria II GX Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.85	—	0.95	0.88	—	0.95	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.71	—	0.79	0.71	—	0.79	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	—	—	0.5 × V_{CCIO}	—	0.48 × V_{CCIO}	0.5 × V_{CCIO}	0.52 × V_{CCIO}	0.3	—

Table 1–31 lists the HSTL I/O standards for Arria II GZ devices.

Table 1–31. Differential HSTL I/O Standards for Arria II GZ Devices

I/O Standard	V_{CCIO} (V)			$V_{DIF(DC)}$ (V)		$V_{X(AC)}$ (V)			$V_{CM(DC)}$ (V)			$V_{DIF(AC)}$ (V)	
	Min	Typ	Max	Min	Max	Min	Typ	Max	Min	Typ	Max	Min	Max
HSTL-18 Class I	1.71	1.8	1.89	0.2	—	0.78	—	1.12	0.78	—	1.12	0.4	—
HSTL-15 Class I, II	1.425	1.5	1.575	0.2	—	0.68	—	0.9	0.68	—	0.9	0.4	—
HSTL-12 Class I, II	1.14	1.2	1.26	0.16	V_{CCIO} + 0.3	—	0.5 × V_{CCIO}	—	0.4 × V_{CCIO}	0.5 × V_{CCIO}	0.6 × V_{CCIO}	0.3	V_{CCIO} + 0.48

Table 1–32 lists the differential I/O standard specifications for Arria II GX devices.

Table 1–32. Differential I/O Standard Specifications for Arria II GX Devices *(Note 1)*

I/O Standard	V_{CCIO} (V)			V_{ID} (mV)			V_{ICM} (V) *(2)*		V_{OD} (V) *(3)*			V_{OCM} (V)		
	Min	Typ	Max	Min	Cond.	Max	Min	Max	Min	Typ	Max	Min	Typ	Max
2.5 V LVDS	2.375	2.5	2.625	100	V_{CM} = 1.25 V	—	0.05	1.80	0.247	—	0.6	1.125	1.25	1.375
RSDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.1	0.2	0.6	0.5	1.2	1.4
Mini-LVDS *(4)*	2.375	2.5	2.625	—	—	—	—	—	0.25	—	0.6	1	1.2	1.4
LVPECL *(5)*	2.375	2.5	2.625	300	—	—	0.6	1.8	—	—	—	—	—	—
BLVDS *(6)*	2.375	2.5	2.625	100	—	—	—	—	—	—	—	—	—	—

Notes to Table 1–32:

(1) The 1.5 V PCML transceiver I/O standard specifications are described in "Transceiver Performance Specifications" on page 1–21.

(2) V_{IN} range: 0 <= V_{IN} <= 1.85 V.

(3) R_L range: 90 <= RL <= 110 Ω.

(4) The RSDS and mini-LVDS I/O standards are only supported for differential outputs.

(5) The LVPECL input standard is supported at the dedicated clock input pins (GCLK) only.

(6) There are no fixed V_{ICM}, V_{OD}, and V_{OCM} specifications for BLVDS. These specifications depend on the system topology.

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* **(Part 3 of 7)**

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
`fixedclk` clock frequency	PCIe Receiver Detect	—	125	—	—	125	—	—	125	—	—	125	—	MHz
`reconfig_ clk` clock frequency	Dynamic reconfig. clock frequency	2.5/ 37.5 *(4)*	—	50	2.5/ 37.5 *(4)*	—	50	2.5/ 37.5 *(4)*	—	50	2.5/ 37.5 *(4)*	—	50	MHz
Delta time between `reconfig_ clks` *(5)*	—	—	—	2	—	—	2	—	—	2	—	—	2	ms
Transceiver block minimum power-down pulse width	—	—	1	—	—	1	—	—	1	—	—	1	—	µs
Receiver														
Supported I/O Standards	1.4-V PCML, 1.5-V PCML, 2.5-V PCML, 2.5-V PCML, LVPECL, and LVDS													
Data rate *(13)*	—	600	—	6375	600	—	3750	600	—	3750	600	—	3125	Mbps
Absolute V_{MAX} for a receiver pin *(6)*	—	—	—	1.5	—	—	1.5	—	—	1.5	—	—	1.5	V
Absolute V_{MIN} for a receiver pin	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	-0.4	—	—	V
Maximum peak-to-peak differential input voltage V_{ID} (diff p-p)	V_{ICM} = 0.82 V setting	—	—	2.7	—	—	2.7	—	—	2.7	—	—	2.7	V
	V_{ICM} =1.1 V setting *(7)*	—	—	1.6	—	—	1.6	—	—	1.6	—	—	1.6	V

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* **(Part 5 of 7)**

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
LTD lock time *(11)*	—	0	100	4000	0	100	4000	0	100	4000	0	100	4000	ns
Data lock time from `rx_freqlocked` *(12)*	—	—	—	4000	—	—	4000	—	—	4000	—	—	4000	ns
Programmable DC gain	DC Gain Setting = 0	—	0	—	—	0	—	—	0	—	—	0	—	dB
	DC Gain Setting = 1	—	3	—	—	3	—	—	3	—	—	3	—	dB
	DC Gain Setting = 2	—	6	—	—	6	—	—	6	—	—	6	—	dB
Transmitter														
Supported I/O Standards	1.5-V PCML													
Data rate	—	600	—	6375	600	—	3750	600	—	3750	600	—	3125	Mbps
V_{OCM}	0.65 V setting	—	650	—	—	650	—	—	650	—	—	650	—	mV
Differential on-chip termination resistors	100–Ω setting	—	100	—	—	100	—	—	100	—	—	100	—	Ω
Return loss differential mode	PCIe	50 MHz to 1.25 GHz: –10dB												
	XAUI	312 MHz to 625 MHz: –10dB 625 MHz to 3.125 GHz: –10dB/decade slope												
Return loss common mode	PCIe	50 MHz to 1.25 GHz: –6dB												
Rise time *(2)*	—	50	—	200	50	—	200	50	—	200	50	—	200	ps
Fall time	—	50	—	200	50	—	200	50	—	200	50	—	200	ps

Table 1–34. Transceiver Specifications for Arria II GX Devices *(Note 1)* **(Part 6 of 7)**

Symbol/ Description	Condition	I3			C4			C5 and I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Intra-differential pair skew	—	—	—	15	—	—	15	—	—	15	—	—	15	ps
Intra-transceiver block skew	PCIe ×4	—	—	120	—	—	120	—	—	120	—	—	120	ps
Inter-transceiver block skew	PCIe ×8	—	—	300	—	—	300	—	—	300	—	—	300	ps
CMU PLL0 and CMU PLL1														
CMU PLL lock time from `CMUPLL_reset` deassertion	—	—	—	100	—	—	100	—	—	100	—	—	100	µs
PLD-Transceiver Interface														
Interface speed	—	25	—	320	25	—	240	25	—	240	25	—	200	MHz

Table 1–35 lists the transceiver specifications for Arria II GZ devices.

Table 1–35. Transceiver Specifications for Arria II GZ Devices (Part 1 of 5)

Symbol/ Description	Conditions	–C3 and –I3 *(1)*			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Reference Clock								
Supported I/O Standards	1.2-V PCML, 1.5-V PCML, 2.5-V PCML, Differential LVPECL, LVDS, and HCSL							
Input frequency from `REFCLK` input pins	—	50	—	697	50	—	637.5	MHz
Phase frequency detector (CMU PLL and receiver CDR)	—	50	—	325	50	—	325	MHz
Absolute V_{MAX} for a `REFCLK` pin	—	—	—	1.6	—	—	1.6	V
Operational V_{MAX} for a `REFCLK` pin	—	—	—	1.5	—	—	1.5	V
Absolute V_{MIN} for a `REFCLK` pin	—	-0.4	—	—	-0.4	—	—	V
Rise/fall time *(2)*	—	—	—	0.2	—	—	0.2	UI
Duty cycle	—	45	—	55	45	—	55	%
Peak-to-peak differential input voltage	—	200	—	1600	200	—	1600	mV
Spread-spectrum modulating clock frequency	PCIe	30	—	33	30	—	33	kHz
Spread-spectrum downspread	PCIe	—	0 to -0.5%	—	—	0 to -0.5%	—	—
On-chip termination resistors	—	—	100	—	—	100	—	Ω
V_{ICM} (AC coupled)	—	1100 ± 10%			1100 ± 10%			mV
V_{ICM} (DC coupled)	HCSL I/O standard for PCIe reference clock	250	—	550	250	—	550	mV
Transmitter REFCLK Phase Noise	10 Hz	—	—	-50	—	—	-50	dBc/Hz
	100 Hz	—	—	-80	—	—	-80	dBc/Hz
	1 KHz	—	—	-110	—	—	-110	dBc/Hz
	10 KHz	—	—	-120	—	—	-120	dBc/Hz
	100 KHz	—	—	-120	—	—	-120	dBc/Hz
	≥ 1 MHz	—	—	-130	—	—	-130	dBc/Hz
Transmitter REFCLK Phase Jitter (rms) for 100 MHz REFCLK *(3)*	10 KHz to 20 MHz	—	—	3	—	—	3	ps
R_{REF}	—	—	2000 ± 1%	—	—	2000 ± 1%	—	Ω

Table 1–40. Transceiver Block Jitter Specifications for Arria II GX Devices *(Note 1)* **(Part 2 of 10)**

Symbol/ Description	Conditions	I3			C4			C5, I5			C6			Unit
		Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	Min	Typ	Max	
Jitter tolerance at 2488.32 Mbps	Jitter frequency = 0.06 KHz Pattern = PRBS15	> 15			> 15			> 15			> 15			UI
	Jitter frequency = 100 KHZ Pattern = PRBS15	> 1.5			> 1.5			> 1.5			> 1.5			UI
	Jitter frequency = 1 MHz Pattern = PRBS15	> 0.15			> 0.15			> 0.15			> 0.15			UI
	Jitter frequency = 10 MHz Pattern = PRBS15	> 0.15			> 0.15			> 0.15			> 0.15			UI
XAUI Transmit Jitter Generation *(3)*														
Total jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.3	—	—	0.3	—	—	0.3	—	—	0.3	UI
Deterministic jitter at 3.125 Gbps	Pattern = CJPAT	—	—	0.17	—	—	0.17	—	—	0.17	—	—	0.17	UI
XAUI Receiver Jitter Tolerance *(3)*														
Total jitter	—	> 0.65			> 0.65			> 0.65			> 0.65			UI
Deterministic jitter	—	> 0.37			> 0.37			> 0.37			> 0.37			UI
Peak-to-peak jitter	Jitter frequency = 22.1 KHz	> 8.5			> 8.5			> 8.5			> 8.5			UI
Peak-to-peak jitter	Jitter frequency = 1.875 MHz	> 0.1			> 0.1			> 0.1			> 0.1			UI
Peak-to-peak jitter	Jitter frequency = 20 MHz	> 0.1			> 0.1			> 0.1			> 0.1			UI
PCIe Transmit Jitter Generation *(4)*														
Total jitter at 2.5 Gbps (Gen1)	Compliance pattern	—	—	0.25	—	—	0.25	—	—	0.25	—	—	0.25	UI

Table 1–41. Transceiver Block Jitter Specifications for Arria II GZ Devices *(Note 1)*, *(2)* **(Part 5 of 7)**

Symbol/ Description	Conditions	–C3 and –I3			–C4 and –I4			Unit
		Min	Typ	Max	Min	Typ	Max	
Sinusoidal jitter tolerance (peak-to-peak)	Jitter Frequency = 38.2 KHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.5			—	—	—	UI
	Jitter Frequency = 3.82 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
	Jitter Frequency = 20 MHz Data rate = 6.375 Gbps Pattern = PRBS31 BER = 10^{-12}	> 0.05			—	—	—	UI
SDI Transmitter Jitter Generation *(12)*								
Alignment jitter (peak-to-peak)	Data rate = 1.485 Gbps (HD) Pattern = color bar Low-frequency roll-off = 100 KHz	0.2	—	—	0.2	—	—	UI
	Data rate = 2.97 Gbps (3G) Pattern = color bar Low-frequency roll-off = 100 KHz	0.3	—	—	0.3	—	—	UI
SDI Receiver Jitter Tolerance *(12)*								
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 15 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 2			> 2			UI
	Jitter frequency = 100 KHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
	Jitter frequency = 148.5 MHz Data rate = 2.97 Gbps (3G) Pattern = single line scramble color bar	> 0.3			> 0.3			UI
Sinusoidal jitter tolerance (peak-to-peak)	Jitter frequency = 20 KHz Data rate = 1.485 Gbps (HD) pattern = 75% color bar	> 1			> 1			UI
	Jitter frequency = 100 KHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
	Jitter frequency = 148.5 MHz Data rate = 1.485 Gbps (HD) Pattern = 75% color bar	> 0.2			> 0.2			UI
SAS Transmit Jitter Generation *(13)*								
Total jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI
Deterministic jitter at 1.5 Gbps (G1)	Pattern = CJPAT	—	—	0.35	—	—	0.35	UI
Total jitter at 3.0 Gbps (G2)	Pattern = CJPAT	—	—	0.55	—	—	0.55	UI

Table 1–44. PLL Specifications for Arria II GX Devices (Part 2 of 3)

Symbol	Description	Min	Typ	Max	Unit
f_{OUT}	Output frequency for internal global or regional clock (–4 Speed Grade)	—	—	500	MHz
	Output frequency for internal global or regional clock (–5 Speed Grade)	—	—	500	MHz
	Output frequency for internal global or regional clock (–6 Speed Grade)	—	—	400	MHz
f_{OUT_EXT}	Output frequency for external clock output (–4 Speed Grade)	—	—	670 *(5)*	MHz
	Output frequency for external clock output (–5 Speed Grade)	—	—	622 *(5)*	MHz
	Output frequency for external clock output (–6 Speed Grade)	—	—	500 *(5)*	MHz
$t_{OUTDUTY}$	Duty cycle for external clock output (when set to 50%)	45	50	55	%
t_{OUTPJ_DC}	Dedicated clock output period jitter ($f_{OUT} \geq 100$ MHz)	—	—	300	ps (p–p)
	Dedicated clock output period jitter ($f_{OUT} < 100$ MHz)	—	—	30	mUI (p–p)
t_{OUTCCJ_DC}	Dedicated clock output cycle-to-cycle jitter ($f_{OUT} \geq 100$ MHz)	—	—	300	ps (p–p)
	Dedicated clock output cycle-to-cycle jitter ($f_{OUT} < 100$ MHz)	—	—	30	mUI (p–p)
f_{OUTPJ_IO}	Regular I/O clock output period jitter ($f_{OUT} \geq 100$ MHz)	—	—	650	ps (p–p)
	Regular I/O clock output period jitter ($f_{OUT} < 100$ MHz)	—	—	65	mUI (p–p)
f_{OUTCCJ_IO}	Regular I/O clock output cycle-to-cycle jitter ($f_{OUT} \geq 100$ MHz)	—	—	650	ps (p–p)
	Regular I/O clock output cycle-to-cycle jitter ($f_{OUT} < 100$ MHz)	—	—	65	mUI (p–p)
$t_{CONFIGPLL}$	Time required to reconfigure PLL scan chains	—	3.5	—	SCANCLK cycles
$t_{CONFIGPHASE}$	Time required to reconfigure phase shift	—	1	—	SCANCLK cycles
$f_{SCANCLK}$	SCANCLK frequency	—	—	100	MHz
t_{LOCK}	Time required to lock from end of device configuration	—	—	1	ms
t_{DLOCK}	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	—	—	1	ms
$f_{CL\ B\ W}$	PLL closed-loop low bandwidth	—	0.3	—	MHz
	PLL closed-loop medium bandwidth	—	1.5	—	MHz
	PLL closed-loop high bandwidth	—	4	—	MHz
t_{PLL_PSERR}	Accuracy of PLL phase shift	—	—	±50	ps
t_{ARESET}	Minimum pulse width on `areset` signal	10	—	—	ns

Table 1–47. DSP Block Performance Specifications for Arria II GZ Devices *(Note 1)* (Part 2 of 2)

Mode	Resources Used	Performance		Unit
	Number of Multipliers	–3	–4	
Double mode	1	440	380	MHz

Notes to Table 1–47:

(1) Maximum is for fully pipelined block with **Round** and **Saturation** disabled.

(2) Maximum for loopback input registers disabled, **Round** and **Saturation** disabled, and pipeline and output registers enabled.

Embedded Memory Block Specifications

Table 1–48 lists the embedded memory block specifications for Arria II GX devices.

Table 1–48. Embedded Memory Block Performance Specifications for Arria II GX Devices

Memory	Mode	Resources Used		Performance				Unit
		ALUTs	Embedded Memory	I3	C4	C5,I5	C6	
Memory Logic Array Block (MLAB)	Single port 64 × 10	0	1	450	500	450	378	MHz
	Simple dual-port 32 × 20 single clock	0	1	270	500	450	378	MHz
	Simple dual-port 64 × 10 single clock	0	1	428	500	450	378	MHz
M9K Block	Single-port 256 × 36	0	1	360	400	360	310	MHz
	Single-port 256 × 36, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	Simple dual-port 256 × 36 single CLK	0	1	360	400	360	310	MHz
	Single-port 256 × 36 single CLK, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	True dual port 512 × 18 single CLK	0	1	360	400	360	310	MHz
	True dual-port 512 × 18 single CLK, with the **read-during-write** option set to **Old Data**	0	1	250	280	250	210	MHz
	Min Pulse Width (clock high time)	—	—	900	850	950	1130	ps
	Min Pulse Width (clock low time)	—	—	730	690	770	920	ps

Periphery Performance

This section describes periphery performance, including high-speed I/O, external memory interface, and IOE programmable delay.

I/O performance supports several system interfaces, for example the high-speed I/O interface, external memory interface, and the PCI/PCI-X bus interface. I/O using SSTL-18 Class I termination standard can achieve up to the stated DDR2 SDRAM interfacing speed with typical DDR2 SDRAM memory interface setup. I/O using general purpose I/O (GPIO) standards such as 3.0, 2.5, 1.8, or 1.5 LVTTL/LVCMOS are capable of typical 200 MHz interfacing frequency with 10pF load.

☞ Actual achievable frequency depends on design- and system-specific factors. You should perform HSPICE/IBIS simulations based on your specific design and system setup to determine the maximum achievable frequency in your system.

High-Speed I/O Specification

Table 1–53 lists the high-speed I/O timing for Arria II GX devices.

Table 1–53. High-Speed I/O Specifications for Arria II GX Devices (Part 1 of 4)

Symbol	Conditions	I3		C4		C5,I5		C6		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
Clock										
f_{HSCLK_IN} (input clock frequency)–Row I/O	Clock boost factor, W = 1 to 40 *(1)*	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_IN} (input clock frequency)–Column I/O	Clock boost factor, W = 1 to 40 *(1)*	5	500	5	500	5	472.5	5	472.5	MHz
f_{HSCLK_OUT} (output clock frequency)–Row I/O	—	5	670	5	670	5	622	5	500	MHz
f_{HSCLK_OUT} (output clock frequency)–Column I/O	—	5	500	5	500	5	472.5	5	472.5	MHz

Table 1–60 lists the DQS phase shift error for Arria II GX devices.

Table 1–60. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GX Devices *(Note 1)*

Number of DQS Delay Buffer	C4	I3, C5, I5	C6	Unit
1	26	30	36	ps
2	52	60	72	ps
3	78	90	108	ps
4	104	120	144	ps

Note to Table 1–60:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a C4 speed grade is ± 78 ps or ± 39 ps.

Table 1–61 lists the DQS phase shift error for Arria II GZ devices.

Table 1–61. DQS Phase Shift Error Specification for DLL-Delayed Clock (t_{DQS_PSERR}) for Arria II GZ Devices *(Note 1)*

Number of DQS Delay Buffer	–3	–4	Unit
1	28	30	ps
2	56	60	ps
3	84	90	ps
4	112	120	ps

Note to Table 1–61:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a 3 speed grade is ± 84 ps or ± 42 ps.

Table 1–62 lists the memory output clock jitter specifications for Arria II GX devices.

Table 1–62. Memory Output Clock Jitter Specification for Arria II GX Devices *(Note 1)*, *(2)*, *(3)*

Parameter	Clock Network	Symbol	–4		–5		–6		Unit
			Min	Max	Min	Max	Min	Max	
Clock period jitter	Global	$t_{JIT(per)}$	-100	100	-125	125	-125	125	ps
Cycle-to-cycle period jitter	Global	$t_{JIT(cc)}$	-200	200	-250	250	-250	250	ps
Duty cycle jitter	Global	$t_{JIT(duty)}$	-100	100	-125	125	-125	125	ps

Notes to Table 1–62:

(1) The memory output clock jitter measurements are for 200 consecutive clock cycles, as specified in the JEDEC DDR2/DDR3 SDRAM standard.

(2) The clock jitter specification applies to memory output clock pins generated using DDIO circuits clocked by a PLL output routed on a global clock network.

(3) The memory output clock jitter stated in Table 1–62 is applicable when an input jitter of 30 ps is applied.

Table 1–68. Glossary (Part 2 of 4)

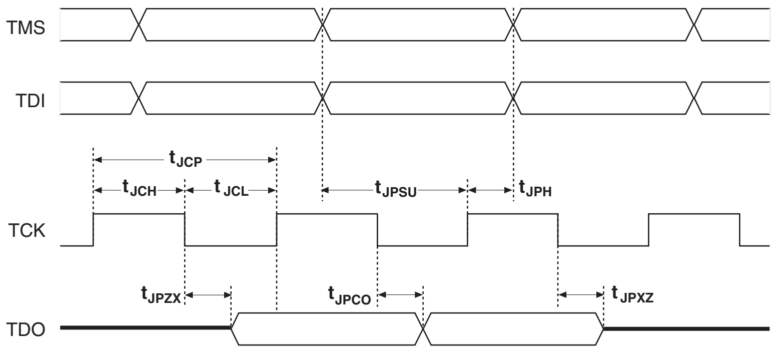
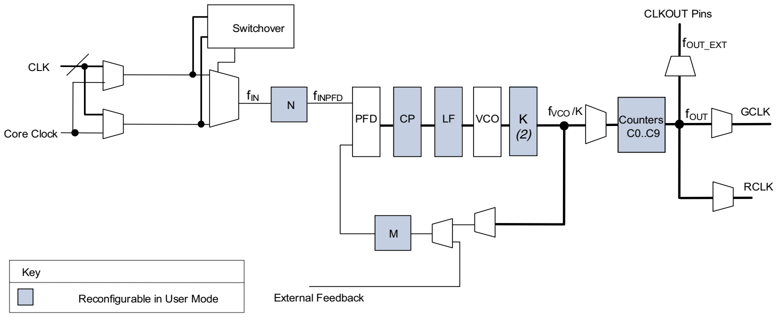
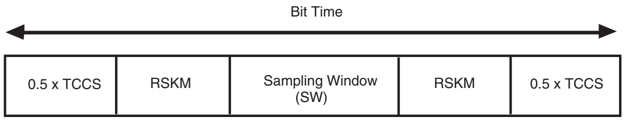
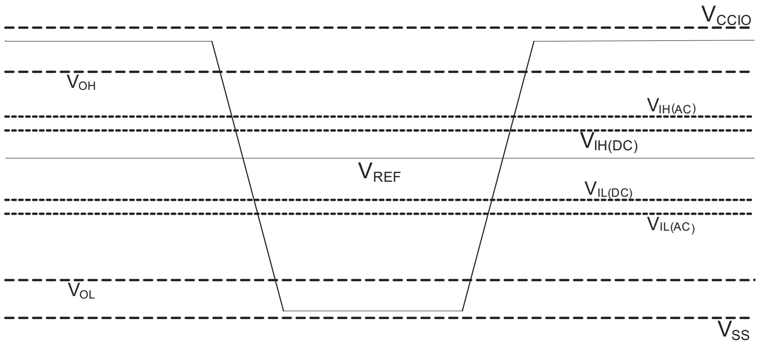
Letter	Subject	Definitions
G, H, I, J	J	High-speed I/O block: Deserialization factor (width of parallel data bus).
	JTAG Timing Specifications	JTAG Timing Specifications: 
K, L, M, N, O, P	PLL Specifications	PLL Specification parameters: **Diagram of PLL Specifications** *(1)*  **Notes:** (1) CoreClock can only be fed by dedicated clock input pins or PLL outputs. (2) This is the VCO post-scale counter K.
Q, R	R_L	Receiver differential input discrete resistor (external to the Arria II device).

Table 1–68. Glossary (Part 3 of 4)

Letter	Subject	Definitions
S	**SW (sampling window)**	The period of time during which the data must be valid in order to capture it correctly. The setup and hold times determine the ideal strobe position within the sampling window: *Timing Diagram* 
	Single-ended Voltage Referenced I/O Standard	The JEDEC standard for SSTL and HSTL I/O standards define both the AC and DC input signal values. The AC values indicate the voltage levels at which the receiver must meet its timing specifications. The DC values indicate the voltage levels at which the final logic state of the receiver is unambiguously defined. After the receiver input has crossed the AC value, the receiver changes to the new logic state. The new logic state is then maintained as long as the input stays beyond the AC threshold. This approach is intended to provide predictable receiver timing in the presence of input waveform ringing: *Single-Ended Voltage Referenced I/O Standard* 
T	**t_C**	High-speed receiver and transmitter input and output clock period.
	TCCS (channel-to-channel-skew)	The timing difference between the fastest and slowest output edges, including t_{CO} variation and clock skew, across channels driven by the same PLL. The clock is included in the TCCS measurement (refer to the *Timing Diagram* figure under **S** in this table).
	t_{DUTY}	High-speed I/O block: Duty cycle on the high-speed transmitter output clock. **Timing Unit Interval (TUI)** The timing budget allowed for skew, propagation delays, and data sampling window. (TUI = 1/(Receiver Input Clock Frequency Multiplication Factor) = t_C/w)
	t_{FALL}	Signal high-to-low transition time (80-20%)
	t_{INCCJ}	Cycle-to-cycle jitter tolerance on the PLL clock input.
	t_{OUTPJ_IO}	Period jitter on the general purpose I/O driven by a PLL.
	t_{OUTPJ_DC}	Period jitter on the dedicated clock output driven by a PLL.
	t_{RISE}	Signal low-to-high transition time (20-80%).